Search for T' → tH in SS dilepton final state

Particle Group Meeting

3rd November

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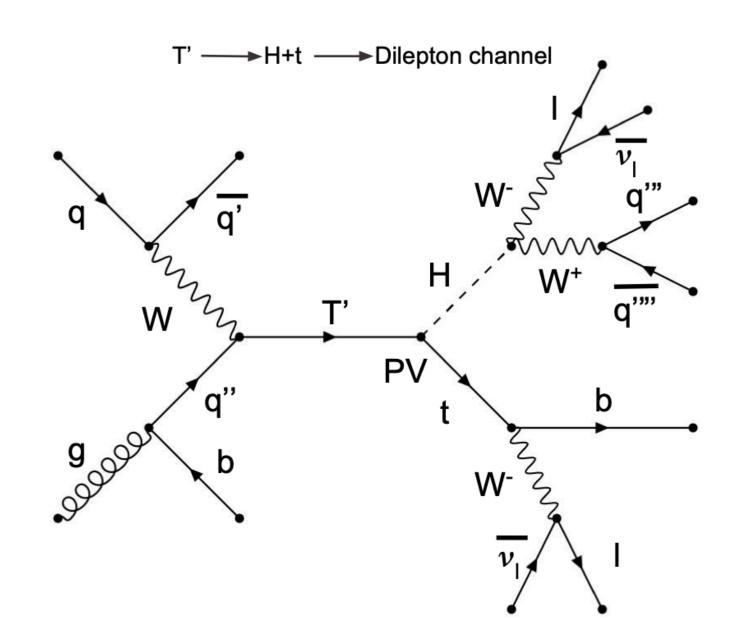
Why T' (Vector Like Quark)?

- Particularly attractive to solve the hierarchy and CKM unitarity problems.
- Quarks for which the left- and right-handed chiral components transform in the same way in the SM electroweak group.
- · VLQ:
 - Charge +2/3
 - Decay to tH (25%), tZ (25%) and tb (50%)

Introduction

- Search for a single-produced VLQ T' decaying into top and Higgs in a SS dilepton final state.
- Three channels considered (μμ/eμ/ee).
- Nominal masses m, range: [600 1200 GeV].
- Full Run 2 (2016-2018) UL data.
- Searching for a resonance in the transverse mass ${\cal M}_T^{T'}$

$$\begin{split} (M_{T}^{T'})^{2} &= \left(\sum_{particles} E_{T}\right)^{2} - \left(\sum_{particles} \overrightarrow{p_{T}}\right)^{2} \\ &= \left(E_{T,lep,Higgs} + E_{T,\nu,Higgs} + E_{T,j1,Higgs} + E_{T,j2,Higgs} + E_{T,lep,top} + E_{T,\nu,top} + E_{T,b,top}\right)^{2} \\ &- \left(\overrightarrow{p_{T,lep,Higgs}} + \overrightarrow{p_{T,\nu,Higgs}} + \overrightarrow{p_{T,j1,Higgs}} + \overrightarrow{p_{T,j2,Higgs}} + \overrightarrow{p_{T,lep,top}} + \overrightarrow{p_{T,\nu,top}} + \overrightarrow{p_{T,\nu,top}}\right)^{2}. \end{split}$$



Event Selection

- HLT Paths (2018):
 - HLT_IsoMu24 for muon
 - HLT_Ele32_WPTight_Gsf for Electron
- Lepton Selection (2018):

Criterion	Mu	ons	Electrons		
Criterion	Fakeable	Tight	Fakeable	Tight	
$p_T \; (\text{GeV})$	> 30	> 30	> 40	> 40	
$ \eta $	< 2.4	< 2.4	< 1.4442 A	ND (> 1.566 OR < 2.5)	
Identification	Medium ID	Medium ID	Loose ID	Tight ID	
Isolation	Loose WP	Tight WP	Loose WP	Tight WP	
$ d_{xy} $ (cm)	< 0.05	< 0.05	< 0.05	< 0.05	
$ d_z $ (cm)	< 0.1	< 0.1	< 0.1	< 0.1	
SIP_{3D}	< 4	< 4	< 4	< 4	
Missing inner hits	-		=0	=0	
Conversion veto	-	-	Yes	Yes	
Tight charge	Yes	Yes	Yes	Yes	

Tight Isolation: $I_{rel} < I_1$ AND $(p_T^{ratio} > I_2 \text{ OR } p_T^{rel} > I_3)$.

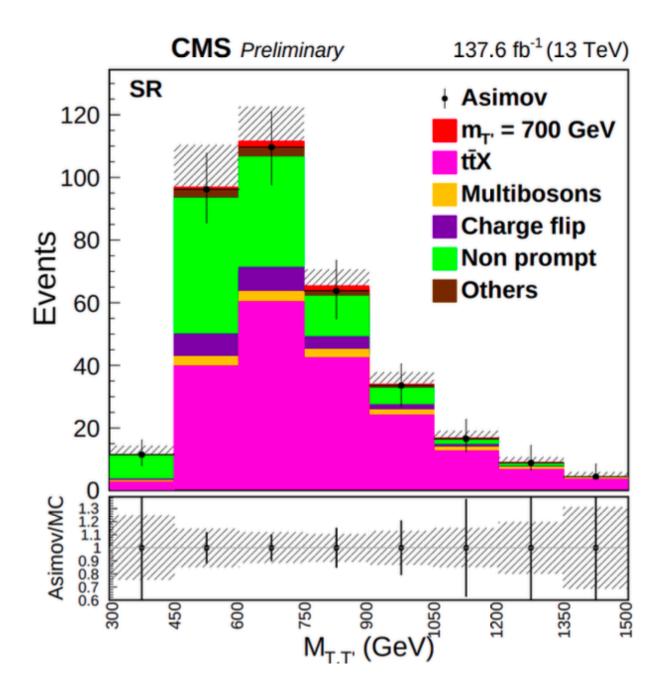
$$p_T^{ratio} = \frac{p_T(\mathbf{l})}{p_T(jet)}, \ p_T^{rel} = \frac{|(\overrightarrow{p}(jet) - \overrightarrow{p}(\mathbf{l})) \times \overrightarrow{p}(\mathbf{l})|}{|\overrightarrow{p}(jet) - \overrightarrow{p}(\mathbf{l})|}$$

Isolation	Muon	0	Electron Tight WP		
Year	2016	2017-2018	2016	2017-2018	
I_1	0.16	0.11	0.12	0.07	
I_2	0.76	0.74	0.80	0.78	
I_3	7.2	6.8	7.2	8.0	

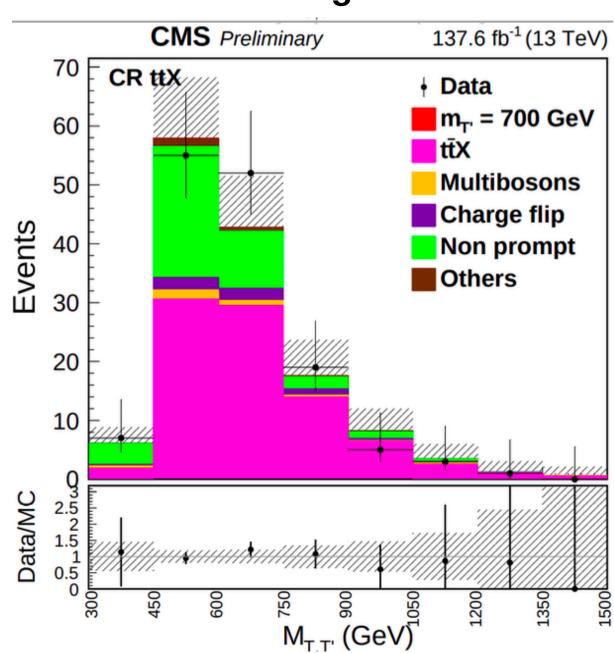
Results

Profile likelihood fit is performed using Combine package.

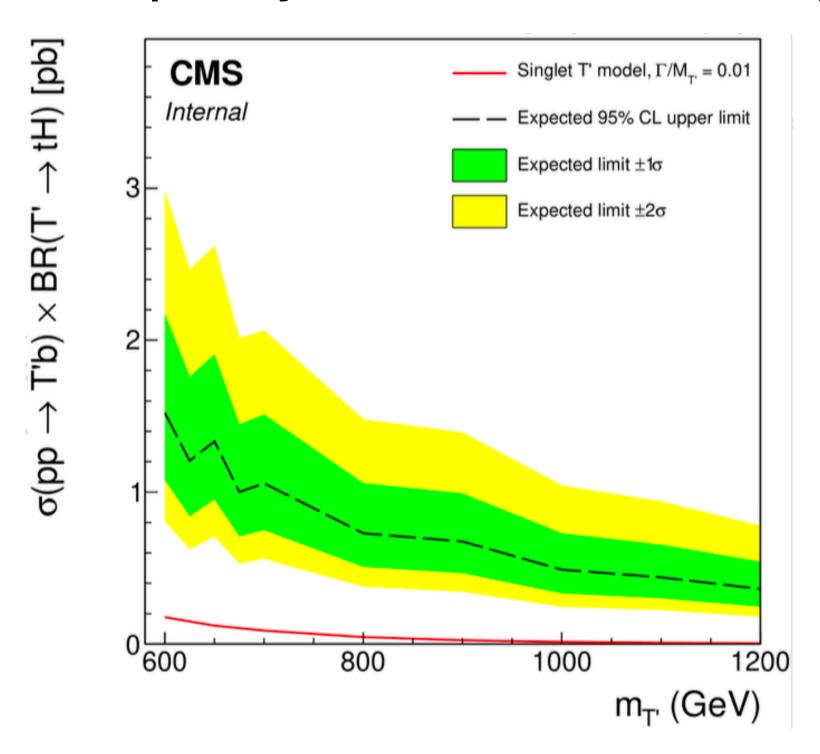
Signal Region



ttX Region



Expected UL at 95% CL of the cross section multiplied by the BR of the T' → Ht decay.



Object Review

Status of the Object reviews:

Explicit green-lights from experts

Category	Name	Status
Conveners		Ongoing.
INT	Agostino De Iorio	Green light
PPD	Antimo Cagnotta & Fabio Iemmi	Green light
GEN	Elise Jourd'huy	Green light
TRIG		Ongoing.
EGM		Ongoing.
MUO		Ongoing.
TAU		Green light
JME		Ongoing.
BTV	Amitav Mitra & Mary Hadley	Green light
STAT		Green light

- TRIG, EGM and MUO comments are related to the extra isolation cut (multilso) which we are applying in our analysis as we have relatively boosted leptons.
 - In this multi-isolation, the cone is varies as a function of the p_T of the lepton.
 - We are checking the impact of replacing this extra isolation cut with the standard isolation in our selection.
- The JME object review is related to one missing uncertainty (JER).
 - We have already added this in our analysis framework.
 - In the next iteration of our results we are expecting to include it.

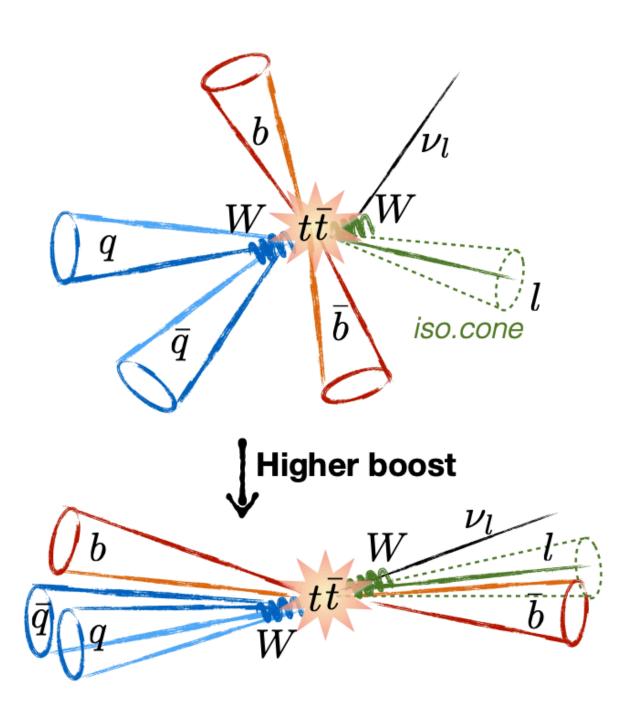
Isolation

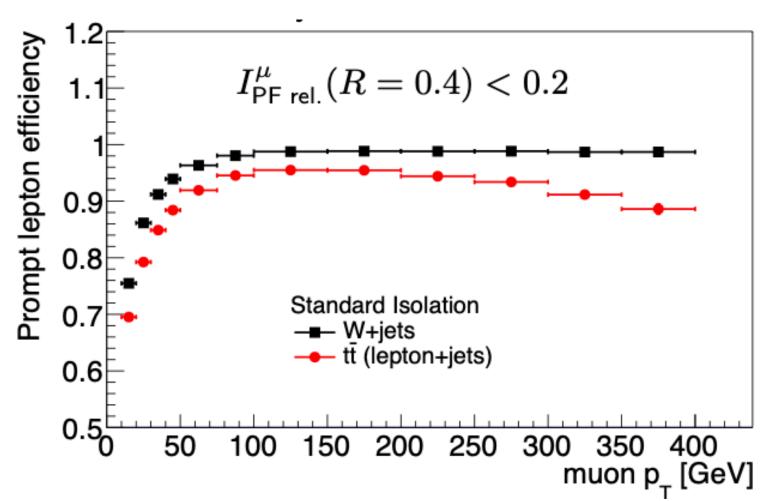
- The SFs are not available for Multi-isolation
- We have switched to Standard Isolation.

• It is not good for boosted scenario. Removes a lot of signal events.

Significance degraded. (results in the next slides.)

We have used Mini-Isolation and Lepton-MVA.





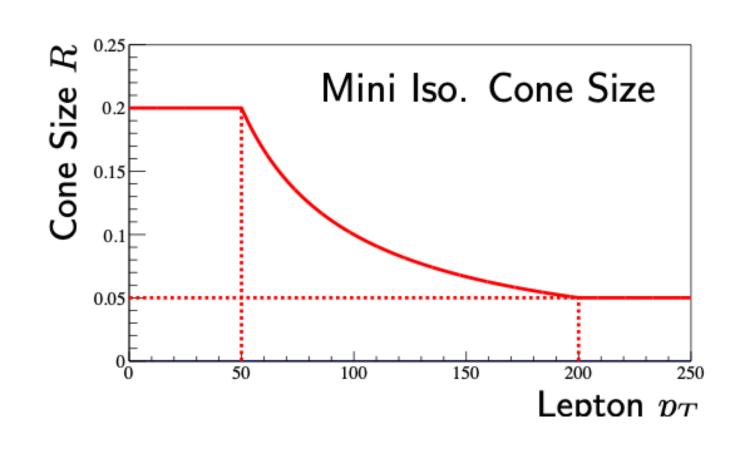
Results with Standard Isolation

• First reproduced Benjamin's results (from his thesis). They are comparable within <1%. 0.266 σ in comparison to 0.267 σ

		Signal	ttX	Multiboson	Flip	Fake	Other Bkgs
Arnab	ee	0.347	13.292	1.653	4.395	8.266	1.821
	em	1.042	34.883	4.339	6.695	33.024	2.658
	mm	0.603	22.964	1.426	0.0	31.321	1.599
	Tot	1.991 -6%	71.138 +11%	7.418	11.089	71.611 +69%	6.078
Benjamin	ee	0.265	10.503	1.215	3.215	4.904	1.169
	em	1.038	31.181	3.710	4.750	18.120	2.047
	mm	0.803	22.378	0.954	0.0	19.097	1.355
	Tot	2.106	64.063	5.878	7.965	42.121	4.571

35% reduction on significance at $M_{T^{\prime}}$ = 700 GeV. It is even worse at 1 TeV, > 50 %

Different Isolation variables available in CMS



For boosted two-body decay:

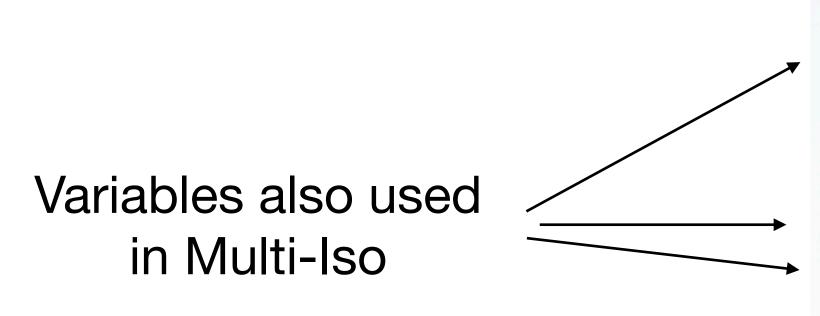
$$\Delta R_{
m daughters} pprox rac{2m_{
m mother}}{p_{T,
m mother}}$$

Mini isolation: use cone size of

$$R = egin{cases} 0.2, & p_{T, \mathsf{lep}} \leq 50 \; \mathsf{GeV} \ rac{10 \; \mathsf{GeV}}{p_{T, \mathsf{lep}}}, & p_{T, \mathsf{lep}} \in (50 \; \mathsf{GeV}, 200 \; \mathsf{GeV}) \ 0.05, & p_{T, \mathsf{lep}} \geq 200 \; \mathsf{GeV} \end{cases}$$

Different Isolation variables available in CMS

Lepton MVA ID



Variables	Description		
рт	Transverse momentum		
η	Pseudorapidity (absolute value)		
rellso0p3	Relative isolation , scalar p_T sum of PF objects in dR = 0.3		
miniRelIsoCharged	Relative mini isolation with p _T -dependent cone size		
miniRelIsoNeutral	including charged (or neutral) PF objects		
jetNDauChargedMVASel	Properties w.r.t. the closest jet (in dR = 0.4) using JEC applied only to its hadronic component:		
jetPtRelv2	number of charged particles in the jet; fraction of the		
min(jetPtRatio,1.5)	lepton momentum in transverse direction to the jet axi ratio between the lepton and jet p _T s; b tagging probabil		
jetBTag	(DeepCSV → DeepJet).		
sip3d	Impact parameters: 3D signed impact parameter significance; transverse and longitudinal impact		
log(dxy)			
log(dz)	parameters w.r.t. primary vertex		
MVA ID score (electrons) / segmentCompatibility (muons)	POG electron MVA ID discriminant (ElectronMVAEstimatorRun2Spring16GeneralPurposeV1 Values → ElectronMVAEstimatorRun2Fall17NolsoV2Values) / compatibility of track segments in the muon system with the expected pattern of a minimum ionizing particle		

Results with Different-Isolation

We are trying several variations other than multi-isolation.

Different Iso		Signal	ttX	Multiboson	Flip	Fake	Other Bkgs	Significance
Multi-Iso	Tot	2.106	64.063	5.878	7.965	42.121	4.571	0.267
Std-Iso	Tot	1.991	71.138	7.418	11.089	71.611	6.078	0.187
Mini-Iso	Tot	2.991	65.08	6.318	8.95	45.611	6.078	0.214
Lepton- MVA Tight	Tot	2.014	63.463	5.948	10.078	50.873	5.78	0.227
Lepton- MVA Medium	Tot	2.289	64.584	6.133	11.073	51.08	4.433	0.264

For the results with Lepton-MVA, we have considered di-lepton trigger paths as well. We are is progress to produce the results for higher mass points.

Back up

Analysis Note: <u>AN-2022/174</u>, PAS: <u>B2G-24-017</u>

Multi-Isolation

• The relative mini isolation I_{mini}^{rel} [54] is defined as follows:

$$I_{mini}^{rel} = \frac{\sum_{R} (p_T(h^{\pm})) + \max\left(0, \sum_{R} (p_T(h^0) + p_T(\gamma) - \rho A \frac{R^2}{0.3})\right)}{p_T(l)},$$
(1)

where ρ is the pileup energy density, A(e) the effective area defined in Tab. 18, and where $\sum_{R} (p_T(h^{\pm}))$, $\sum_{R} (p_T(h^0))$, and $\sum_{R} (p_T(\gamma))$ refer to the sum of the transverse momentum of the respective charged hadrons, neutral hadrons, and photons, within a cone R depending on the electron p_T :

$$R = \frac{10}{\min\left(\max\left(p_T(l), 50\right), 200\right)}.$$
 (2)

Requiring I_{mini}^{rel} below a given threshold ensures that the electron is locally isolated, even in topologies where its transverse momentum exceeds a hundred of GeV. The impact of pileup is mitigated, using the effective area correction. This criterion is applied on top of the cut-based ID criterion.

• p_T^{ratio} is defined as follows:

$$p_T^{ratio} = \frac{p_T(e)}{p_T(jet)},\tag{3}$$

Multi-Isolation

• p_T^{rel} is defined as follows:

$$p_T^{rel} = \frac{\left| \left(\overrightarrow{p}(jet) - \overrightarrow{p}(l) \right) \times \overrightarrow{p}(l) \right|}{\left| \overrightarrow{p}(jet) - \overrightarrow{p}(l) \right|}. \tag{4}$$

Requiring p_T^{rel} above a given threshold allows recovering electrons from accidental overlap with jets. If the jet and the electron are spatially separated, the numerator will be indeed large and the denominator small. The jet energy corrections are only applied to the hadronic part of the jet.

An electron is considered isolated if the following conditions are satisfied:

$$I_{mini}^{rel} < I_1 \text{ AND } (p_T^{ratio} > I_2 \text{ OR } p_T^{rel} > I_3).$$
 (5)

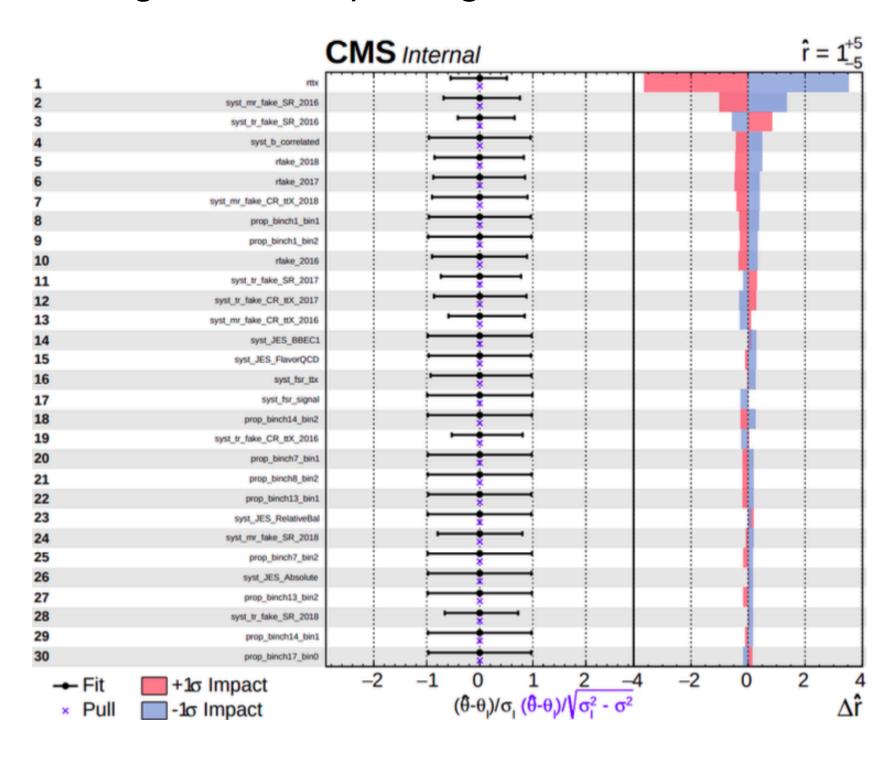
Isolation	Muon WP		Electron WP		
Year	2016 2017-2018		2016	2017-2018	
I_1	0.16	0.11	0.12	0.07	
I_2	0.76	0.74	0.80	0.78	
I_3	7.2	6.8	7.2	8.0	

Table 19: Isolation WPs for both electrons and muons for 2016, 2017 and 2018.

Results

• Profile likelihood fit is performed using Combine package.

Systematic uncertainty source Correlation between regions Correlation between years Correlation between years Luminosity, corr. component Luminosity, uncorr. component Pileup Pileup Pileup JetID L1 Trigger ECAL prefiring B-tagging (bottom), corr. component B-tagging (bottom), uncorr. component B-tagging (light), corr. component B-tagging (light), corr. component B-tagging (light), uncorr. component Correlation B-tagging Dord Correlation Correlation B-tacept DD processes Total except DD processes	cesses cesses cesses cesses cesses cesses cesses cesses cesses cesses cesses
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JES FlavorQCD ✓ ✓ Total except DD proc	cesses
JES RelativeSample ✓ - Total except DD proc	
JES RelativeBal ✓ ✓ Total except DD proc	
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MC modeling MR/Target region Total except DD processes - Total except DD proc	
Top quark p_T reweighting \checkmark Total except DD proc	
PDF \(\sqrt{\text{Total except DD proc}}	
Renormalization and factorization scale Total except DD proc	
ISR ✓ ✓ Total except DD proc	
FSR √ Total except DD proc	
Normalization of backgrounds ✓ ✓ -	



Analysis regions

Preselection (Cut 0)

Muon	Pt > 30 GeV, $ \eta $ < 2.4, tight ID, optimized selection on isolation, distance to Primary Vertex (PV), 3D Impact parameter significance (SIP _{3D}) and charge misreconstruction veto.
Electron	Pt > 40 GeV, $ \eta $ < 2.5, tight ID, optimized selection on isolation, distance to PV, SIP $_{3D}$, number of hits, photon conversion veto and charge misreconstruction veto.
Jet	Pt > 30 GeV, $ \eta $ < 2.4, tight ID and removed overlap between the jets and the leptons in a cone of ΔR < 0.4.
B-jet	Pt > 30 GeV, $ \eta $ < 2.4, tight ID and medium DeepJet WP. Identical overlap condition as the jets.

Signal Selection:

- The two leptons must be back-to-back.
- The T' has a large mass so we expect the 2 leptons and the b-jet to have high p_T.
- The top quark must have a non-hadronic decay.

Cut 1: $\Delta R(l_1, l_2) > 1.8$.

Cut 2: $p_T^{l_1} + p_T^{l_2} > 160 \ GeV$

Cut 3: $\min(|M_{3j} - M_{top}| > 34 \ GeV)$

- Falling $M_T^{T'}$ distribution needed to estimate the background.
- Background efficiency in each $M_T^{T'}$ bin should be the same after each cut to keep the same shape.
- Solution: cut optimization using quantiles of the background yield.

Background: (two types)

- **Fake leptons:** The largest contributor to this category is the $t\bar{t}1l$ process (63.3% of the fake leptons in the SR, with a contribution of the $t\bar{t}X$, $t\bar{t}2l$, tX(W/q), and multiboson processes of 17.9%, 10.1%, 6.4%, and 2.3% respectively).
- Flip leptons: leptons whose charge has been misidentified. The largest contributor to this category is the $t\bar{t}2l$ process (95.3% of the flip leptons in the SR).

$t\bar{t}X$ Control region:

- targets the ttX processes.
- Reverted cut 3.
- one of the two top quarks decaying hadronically.

$t\overline{t}2l$ Measurement region:

- targets the charge flip process.
- · Cut 0 is modified to require 2 OS leptons.
- a top quark pair is produced with both top quarks decaying leptonically.

$t\bar{t}1l$ Measurement region:

- targets the non prompt process.
- Cut 0 is modified to require one of the SS leptons must pass the fakeable requirements but fail the tight requirements.